

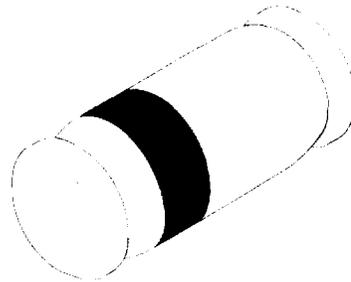
Silicon Epitaxial Planar Diodes

Features

- Electrical data identical with the device
1N4154

Applications

Extreme fast switches



94 9371

Absolute Maximum Ratings

$T_j = 25^\circ\text{C}$

Parameter	Test Conditions	Type	Symbol	Value	Unit
Repetitive peak reverse voltage			V_{RRM}	35	V
Reverse voltage			V_R	25	V
Peak forward surge current	$t_p = 1\mu\text{s}$		I_{FSM}	2	A
Repetitive peak forward current			I_{FRM}	450	mA
Forward current			I_F	200	mA
Average forward current	$V_R = 0$		I_{FAV}	150	mA
Power dissipation			P_V	500	mW
Junction temperature			T_j	175	$^\circ\text{C}$
Storage temperature range			T_{stg}	-65...+175	$^\circ\text{C}$

Maximum Thermal Resistance

$T_j = 25^\circ\text{C}$

Parameter	Test Conditions	Symbol	Value	Unit
Junction ambient	on PC board 50mmx50mmx1.6mm	R_{thJA}	500	K/W

Characteristics

$T_j = 25^\circ\text{C}$

Parameter	Test Conditions	Type	Symbol	Min	Typ	Max	Unit
Forward voltage	$I_F=30\text{mA}$		V_F			1	V
Reverse current	$V_R=25\text{V}$		I_R			100	nA
	$V_R=25\text{V}, T_j=150^\circ\text{C}$		I_R			100	μA
Breakdown voltage	$I_R=5\mu\text{A}, t_p/T=0.01, t_p=0.3\text{ms}$		$V_{(BR)}$	35			V
Diode capacitance	$V_R=0, f=1\text{MHz}, V_{HI}=50\text{mV}$		C_D			4	pF
Reverse recovery time	$I_F=I_R=10\text{mA}, i_R=1\text{mA}$		t_{rr}			4	ns
	$I_F=10\text{mA}, V_R=6\text{V}, i_R=0.1 \times I_R, R_L=100\Omega$		t_{rr}			2	ns

Typical Characteristics ($T_j = 25^\circ\text{C}$ unless otherwise specified)

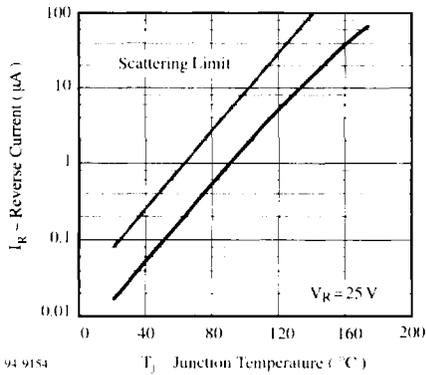


Figure 1: Reverse Current vs. Junction Temperature

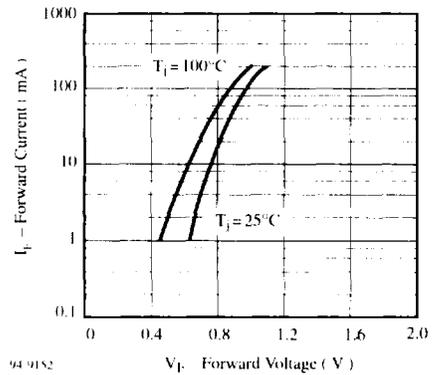


Figure 2: Forward Current vs. Forward Voltage

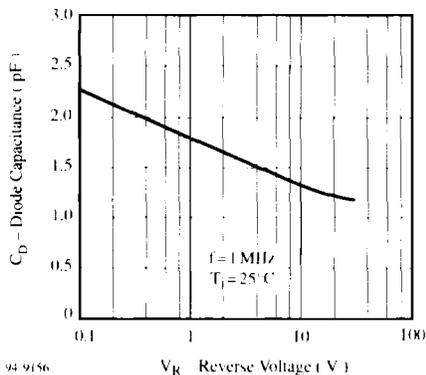


Figure 3: Diode Capacitance vs. Reverse Voltage

Dimensions in mm

